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Form PTO 1449		U.S. DEPARTMEN	T OF COMMERCE	ATTY DOCKET NO.		SERIAL		11604
(Modified)		PATENT AND TRA	DEMARK OFFICE	260781US0PCT	New U.S. PCT Application Based on PCT/EP03/04970			
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LIST OF	REFE	RENCES CITED BY A	PPLICANT	Christian WALSDORFF, et al.				
-				FILING DATE		GROUP		
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				U.S. PATENT DOCUMENTS				
EXAMINER INITIAL		DOCUMENT DATE NAME		NAME	CLASS	SUB FILING DATE CLASS IF APPROPRIATE		
m	A	2 542 961	02/20/51	CHERNIAVSKY, Alexander J. et al.	423	502		
	AB	5 639 436	06/17/97	BENSON, Sidney W. et al.	423	502		
	AC	3 201 201	08/17/65	VAN DIJK, Christiaan P. et al.	423	502		9.5
1	AD	4 828 815	05/09/89	KIYOURA, Tadamitsu et al.	A23	502		
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		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION		
em	AO	1 046 313	10/19/66	GB		YES		NO NO
VIVO	AP	0 233 773 \	08/26/87	EP				NO
-	AQ	1 099 666	05/16/01	EP				NO
	AR	197 48 299	05/07/98	DE (equivalent of US 2002/0172640)				NO
	AS	197 34 412	02/12/98	DE (equivalent of US 5908607)				NO
1000	AT	0 851 834	03/07/01	EP				NO
70 90	AU	0031034	03/01/01					140
	AV		<del>                                     </del>			<del>-,</del>	<del></del> }-	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
	AW							
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	AZ				Addit	ional Refe	rences sh	eet(s) attached
Examiner nyor yen ymyen					Date Considered 9/16/05			
Examiner Date Considered 9/16/05  *Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								